

MOS FIELD EFFECT TRANSISTOR μ PA1911A

P-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The μ PA1911A is a switching device which can be driven directly by a 2.5 V power source.

The μ PA1911A features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

- Can be driven by a 2.5 V power source
- · Low on-state resistance

 $R_{DS(on)1}$ = 115 $m\Omega$ MAX. (Vgs = -4.5 V, ID = -1.5 A)

 $R_{DS(on)2} = 120 \text{ m}\Omega \text{ MAX.} \text{ (V}_{GS} = -4.0 \text{ V}, I_{D} = -1.5 \text{ A})$

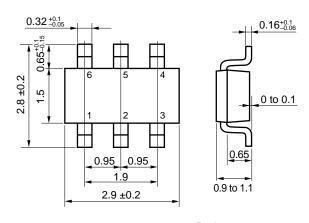
 $R_{DS(on)3} = 190 \text{ m}\Omega \text{ MAX.} (V_{GS} = -2.5 \text{ V}, I_{D} = -1.0 \text{ A})$

ORDERING INFORMATION

PART NUMBER	PACKAGE
μPA1911ATE ^{Note}	SC-95 (Mini Mold Thin Type)

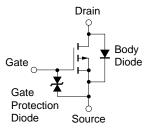
Note Marking: TK

PACKAGE DRAWING (Unit: mm)



1, 2, 5, 6 : Drain 3 : Gate 4 : Source

EQUIVALENT CIRCUIT



ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	-20	V
Gate to Source Voltage (Vps = 0 V)	Vgss	∓ 12	V
Drain Current (DC)	ID(DC)	∓ 2.5	Α
Drain Current (pulse) Note1	D(pulse)	∓ 10	Α
Total Power Dissipation	P _{T1}	0.2	W
Total Power Dissipation (T _A = 25°C) Note2	PT2	2	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to +150	°C

Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

2. Mounted on FR-4 board, $t \le 5$ sec.

Remark

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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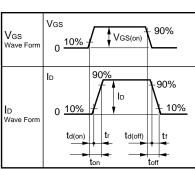


ELECTRICAL CHARACTERISTICS (TA = 25°C)

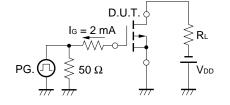
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V _{DS} = -20 V, V _{GS} = 0 V			-10	μΑ
Gate Leakage Current	Igss	V _{GS} = ±12 V, V _{DS} = 0 V			∓ 10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = -10 V, I _D = -1 mA	-0.5	-1.0	-1.5	V
Forward Transfer Admittance	yfs	VDS = -10 V, ID = -1.5 A	1	5.4		S
Drain to Source On-state Resistance	RDS(on)1	V _{GS} = -4.5 V, I _D = -1.5 A		82	115	mΩ
	RDS(on)2	Vgs = -4.0 V, ID = -1.5 A		86	120	mΩ
	RDS(on)3	V _{GS} = -2.5 V, I _D = -1.0 A		122	190	mΩ
Input Capacitance	Ciss	Vps = -10 V		370		pF
Output Capacitance	Coss	V _{GS} = 0 V		110		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		40		pF
Turn-on Delay Time	t d(on)	$V_{DD} = -10 \text{ V}, I_D = -1.5 \text{ A}$		130		ns
Rise Time	t r	V _{GS} = -4.0 V		230		ns
Turn-off Delay Time	t d(off)	R _G = 10 Ω		470		ns
Fall Time	t f			380		ns
Total Gate Charge	Q _G	V _{DD} = -10 V		2.3		nC
Gate to Source Charge	Qgs	I _D = -2.5 A		1.0		nC
Gate to Drain Charge	Q _{GD}	V _{GS} = -4.0 V		1.0		nC
Body Diode Forward Voltage	V _{F(S-D)}	I _F = 2.5 A, V _{GS} = 0 V		0.84		V
Reverse Recovery Time	trr	I _F = 2.5 A, V _{GS} = 0 V		14		ns
Reverse Recovery Charge	Qrr	$di/dt = 10 A/\mu s$		1.4		nC

TEST CIRCUIT 1 SWITCHING TIME

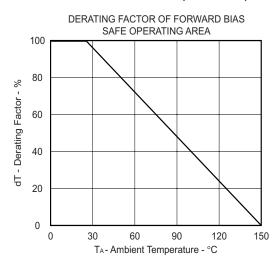
PG. $\bigcap_{RG} R_G = 10 \Omega$ V_{GS} $V_{Mave Form}$ $V_{Mave For$



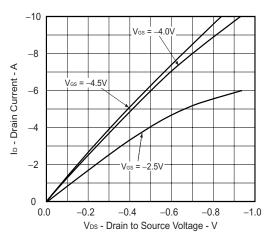
TEST CIRCUIT 2 GATE CHARGE



TYPICAL CHARACTERISTICS (TA = 25°C)

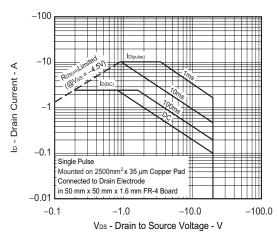


DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE

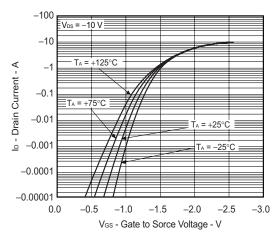


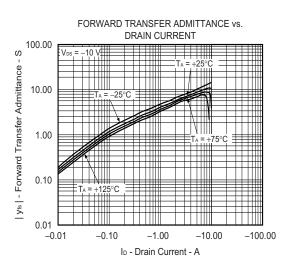
GATE TO SOURCE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE > -1.5 VD S = -10 V ID = -1 mA VD S = -10 V ID = -1 mA Toh - Channel Temperature - °C

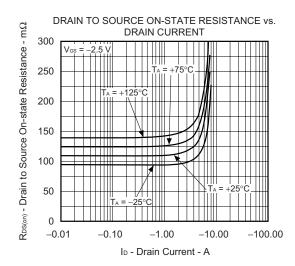
FORWARD BIAS SAFE OPERATING AREA

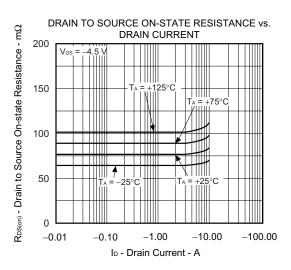


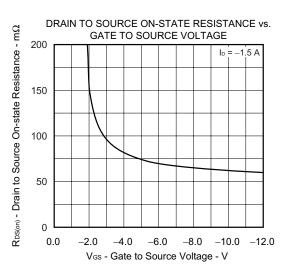
FORWARD TRANSFER CHARACTERISTICS

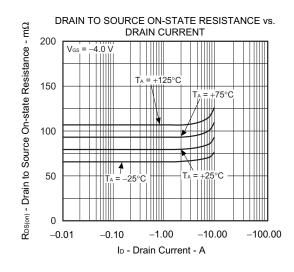


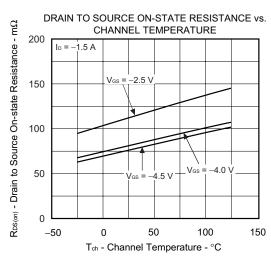




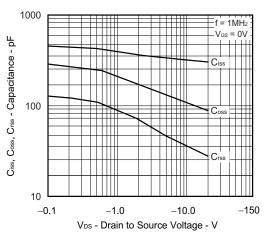




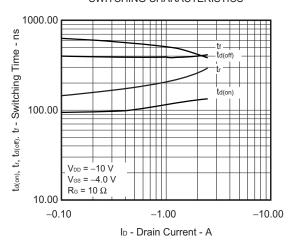




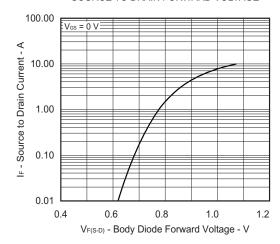




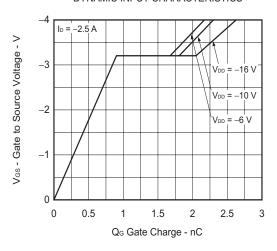
SWITCHING CHARACTERISTICS



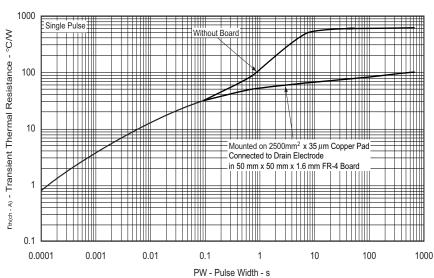
SOURCE TO DRAIN FORWARD VOLTAGE



DYNAMIC INPUT CHARACTERISTICS



TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



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[MEMO]

NEC μ PA1911A

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